





PCN Number:	20221020003.1		PCN Date:	October 21, 2022	
Title:	Qualification of additional Fab site (RFAB) and additional Assembly site (TIPI) for select LBC8LV devices				
Customer Contact:	PCN Manager		Dept:	Quality Services	
Proposed 1st Ship Date:	Jan 21, 2023		Sample requests accepted until:	Nov 21, 2022*	
*Sample requests received after Nov 21, 2022 will not be supported.					
Change Type:					
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Site
<input checked="" type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Material
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input checked="" type="checkbox"/>	Wafer Fab Site
<input checked="" type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input checked="" type="checkbox"/>	Wafer Fab Materials
		<input type="checkbox"/>		<input type="checkbox"/>	Wafer Fab Process
PCN Details					
Description of Change:					
Texas Instruments is pleased to announce the qualification of an additional fab (RFAB) and assembly site (TIPI) option for the devices listed in the "Product Affected" section.					
Current Site			Additional Site		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
DP1DM5	LBC8LV	200 mm	RFAB	LBC8LV	300 mm
Material and Package marking differences between Assembly sites					
	TFME		TIPI		
Wire type	1.0mil Au		0.96mil Cu		
Mount compound	A-09		4226215		
Mold compound	R-13		4222198		
Package Marking					
	***** = BINARY DATECODE  = PIN 1 STRIPE		***** = BINARY DATECODE  = PIN 1 STRIPE		
Reason for Change:					
Continuity of Supply					
1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties 2) Maximize flexibility within our Assembly/Test production sites. 3) Cu is easier to obtain and stock					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):					
None					
Impact on Environmental Ratings:					
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.					
<input type="checkbox"/> RoHS	<input type="checkbox"/> REACH	<input type="checkbox"/> Green Status	<input type="checkbox"/> IEC 62474		

<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change
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Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	DM5	USA	Dallas
RFAB	RFB	USA	Richardson

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
TFME	NFM	CHN	Chongchuan
TIPI	PHI	PHL	Baguio City

Sample product shipping label (not actual product label)

Product Affected:

SN6505ADBVR	SN6505ADBVT	SN6505BDBVR	SN6505BDBVT
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Qualification Report

Approve Date 18-OCTOBER -2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN6505ADBVR	QBS Reference: TLV2401QDBVRQ1
HAST	A2	Biased HAST	130C	96 Hours	-	3/231/0
UHAST	A3	Autodave	121C/15psig	96 Hours	1/77/0	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-
HTOL	B1	Life Test	150C	408 Hours	-	-
ELFR	B2	Early Life Failure Rate	150C	24 Hours	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0

SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-

Type	#	Test Name	Condition	Duration	QBS Reference: <u>UCC27517AQDBVRQ1</u>	QBS Reference: <u>AMC23C12QDWVRQ1</u>
HAST	A2	Biased HAST	130C	96 Hours	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	3/231/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	3/135/0	-
HTOL	B1	Life Test	150C	408 Hours	-	3/231/0
ELFR	B2	Early Life Failure Rate	150C	24 Hours	-	3/2400/0
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	3/30/0	-
ESD	E2	ESD CDM	-	250 Volts	-	-
ESD	E2	ESD HBM	-	1000 Volts	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	-	-

QBS: Qual By Similarity

Qual Device SN6505ADBVR is qualified at MSL1 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/Green/Pb-free>
Status: Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	PCN_ww_admin_team@list.ti.com

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